



A3L:210DT.XXH

VOLTAGE RATINGS

Part Number	V _{RRM} , V _R (V) Max. rep. peak reverse voltage		V _{RSM} , V _R (V) Max. non- rep. peak reverse voltage T _J = 25 to 125°C
	T _J = 0 to 125°C	T _J = -40 to 0°C	
A3L:210TD.02H	200	200	300
A3L:210TD.04H	400	400	500
A3L:210TD.06H	600	600	700
A3L:210TD.08H	800	800	900
A3L:210TD.10H	1000	1000	1100
A3L:210TD.12H	1200	1200	1300
A3L:210TD.14H	1400	1330	1500
A3L:210TD.16H	1600	1520	1700

MAXIMUM ALLOWABLE RATINGS

PARAMETER	VALUE	UNITS	NOTES
T _J Junction Temperature	-40 to 125	°C	-
T _{stg} Storage Temperature	-40 to 150	°C	-
I _{F(AV)}	210	A	
	85	°C	180°half sine wave
I _{F(RMS)} Nom. RMS current	466	A	-
I _{FSM} Max. Peak non-rep. surge current	6.32 6.89 7.2 7.85	kA	50 Hz half cycle sine wave 60 Hz half cycle sine wave 50 Hz half cycle sine wave 60 Hz half cycle sine wave Initial T _J = 125°C, rated V _{RRM} applied after surge. Initial T _J = 125°C, no voltage applied after surge.
I ² t Max. I ² t capability	206 225 235 256	kA ² s	t = 10ms t = 8.3 ms t = 10ms t = 8.3 ms Initial T _J = 125°C, rated V _{RRM} applied after surge. Initial T _J = 125°C, no voltage applied after surge.
I ² t ^{1/2} Max. I ² t ^{1/2} capability	2810	kA ² s ^{1/2}	Initial T _J = 125°C, no voltage applied after surge. for time t _x = I ² t ^{1/2} * t _x ^{1/2} . (0.1 < t _x < 10ms).
di/dt Max. Non-repetitive rate-of-rise current	500	A/μs	T _J = 125°C, V _D = V _{DRM} , I _{TM} = 1600A. Gate pulse: 20V, 20Ω, 10μs, 0.5μs rise time, Max. repetitive di/dt is approximately 40% of non-repetitive value.
P _{GM} Max. Peak gate power	10	W	tp < 5 ms
P _{G(AV)} Max. Av. gate power	3	W	-
+I _{GM} Max. Peak gate current	150	mA	tp < 5 ms
-V _{GM} Max. Peak negative gate voltage	2	V	-
F Mounting Force	3(5)	N.m	Upper connectors(Heatsink)



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CHARACTERISTICS

PARAMETER	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
V_{TM} peak on-state voltage	---	---	1.47	V	Initial $T_J = 25^\circ\text{C}$, 50-60Hz half sine, $I_{\text{peak}} = 659\text{A}$.
$V_{T(TO)}$ Threshold voltage	---	---	0.91	V	$T_J = 125^\circ\text{C}$ Av. power = $V_{T(TO)} * I_{T(AV)} + r_T * [I_{T(RMS)}]^2$, 180 Half Sine.
r_T Slope resistance	---	---	0.82	$\text{m}\Omega$	Use low values for $I_{TM} < \pi$ rated $I_{T(AV)}$
I_L Latching current	---	---	200	mA	$T_C = 125^\circ\text{C}$, 12V anode. Gate pulse: 10V, 20 Ω , 100 μs .
I_H Holding current	---	---	500	mA	$T_C = 25^\circ\text{C}$, 12V anode. Initial $I_T = 15\text{A}$.
t_d Delay time	---	0.7	1.5	μs	$T_C = 25^\circ\text{C}$, $V_D = V_{DRM}$, 50A resistive load. Gate pulse: 10V, 20 Ω , 10 μs , 1 μs rise time.
t_q Turn-off time	---	125	200	μs	$T_J = 125^\circ\text{C}$, $I_{TM} = 500\text{A}$, $di/dt = 25\text{A}/\mu\text{s}$, $V_R = 50\text{V}$. $dv/dt = 20\text{V}/\mu\text{s}$ lin. to rated V_{DRM} . Gate: 0V, 100 Ω .
dv/dt Critical rate-of-rise of off-state voltage	80	140	---	V/ μs	$T_J = 125^\circ\text{C}$. Exp. to 100% or lin. Higher dv/dt values available. To 80% V_{DRM} , gate open.
	---	---	1000		$T_J = 125^\circ\text{C}$, Exp. To 67% V_{DRM} , gate open.
I_{RM}, I_{DM} Peak reverse and off-state current	---	10	50	mA	$T_J = 125^\circ\text{C}$, Rated V_{RRM} and V_{DRM} , gate open.
I_{GT} DC gate current to trigger	---	---	300	mA	$T_C = -40^\circ\text{C}$
	50	80	150		$T_C = 25^\circ\text{C}$ +12V anode-to-cathode. For recommended gate drive see "Gate Characteristics" figure.
V_{GT} DC gate voltage to trigger	4	---	---	V	$T_C = -40^\circ\text{C}$
	2	---	2.5		$T_C = 25^\circ\text{C}$
V_{GD} DC gate voltage not to trigger	---	---	0.3	V	$T_C = 25^\circ\text{C}$, Max. Value which will not trigger with rated V_{DRM} anode.
R_{thJC} Thermal resistance, junction-to-case	---	---	0.076	$^\circ\text{C}/\text{W}$	DC operation, single side cooled.
	---	---	0.08	$^\circ\text{C}/\text{W}$	180 sine wave, single side cooled.
	---	---	0.084	$^\circ\text{C}/\text{W}$	120 rectangular wave, single side cooled.
R_{thCS} Thermal resistance, case-to-sink	---	---	0.02	$^\circ\text{C}/\text{W}$	Mtg. Surface smooth, flat and greased. Single side cooled.
wt Weight	---	500(18)	---	g(oz.)	---

Maximum Allowable Case Temperature

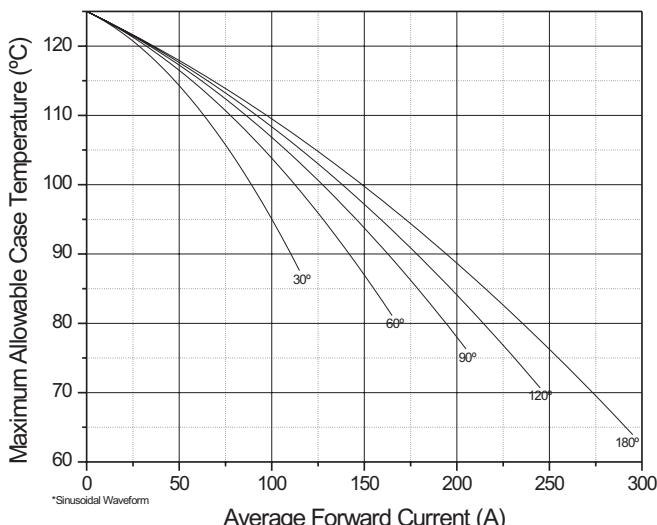


Fig. 1 - Current Ratings Characteristics

Maximum Allowable Case Temperature

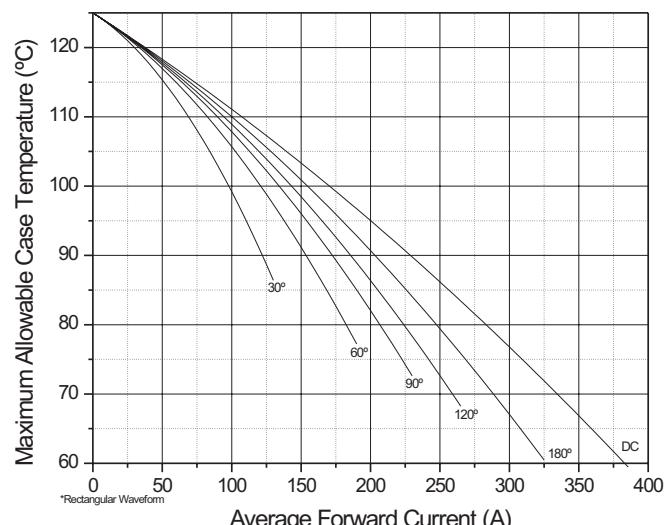


Fig. 2 - Current Ratings Characteristics



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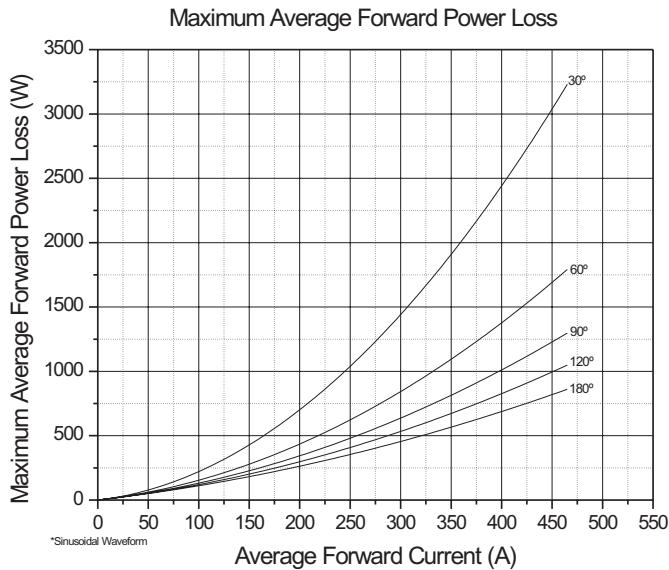


Fig.3 -Forward Power Loss Characteristics

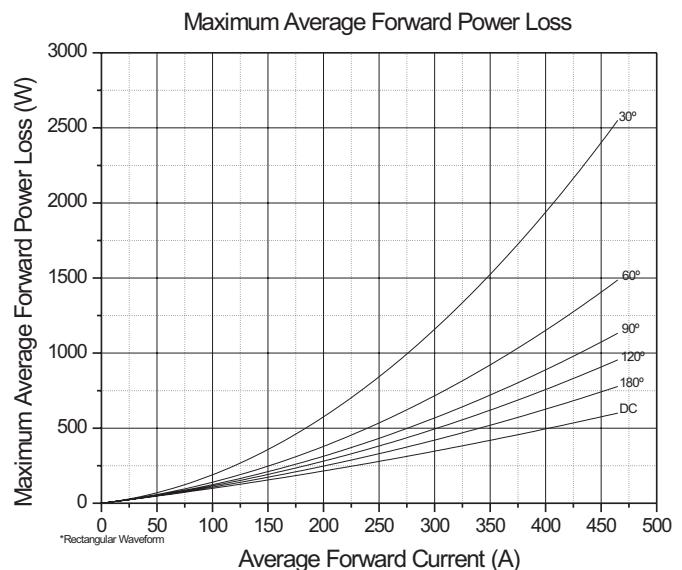


Fig. 4 - Forward Power Loss Characteristics

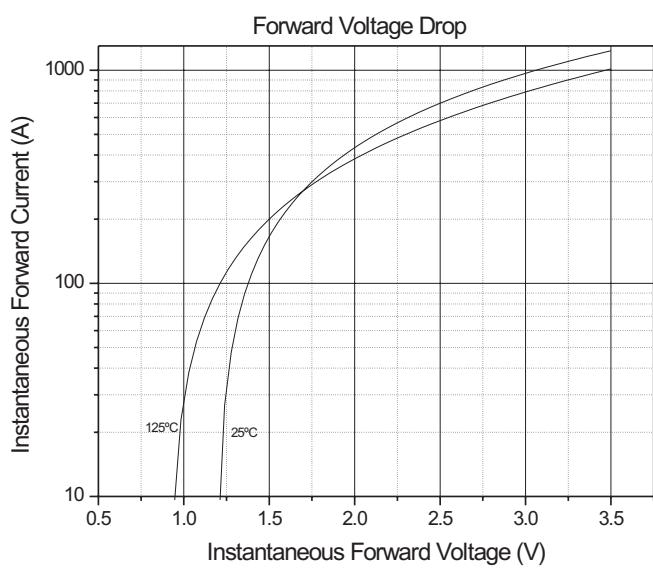


Fig. 5 - Forward Voltage Drop Characteristics

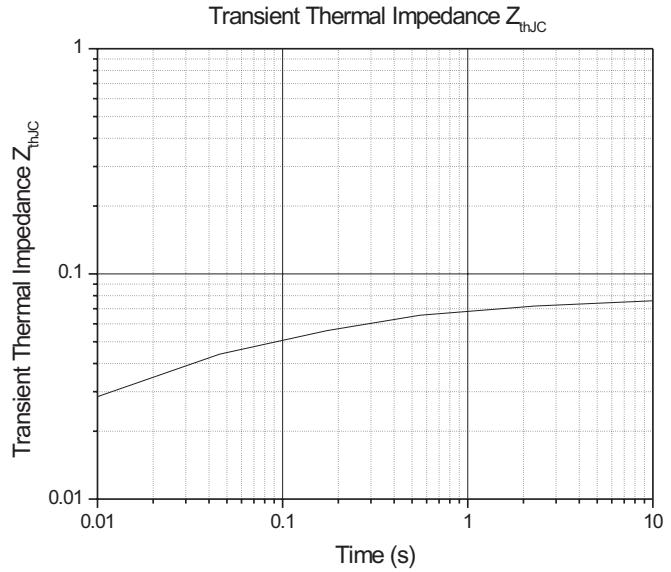


Fig. 6 - Transient Thermal Impedance



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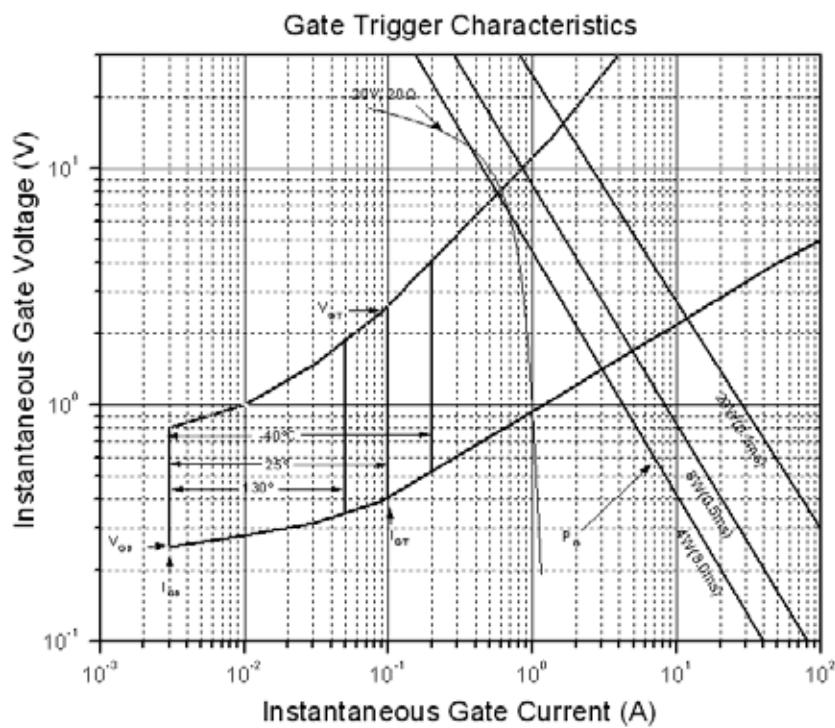


Fig. 7 - Gate Trigger Characteristics

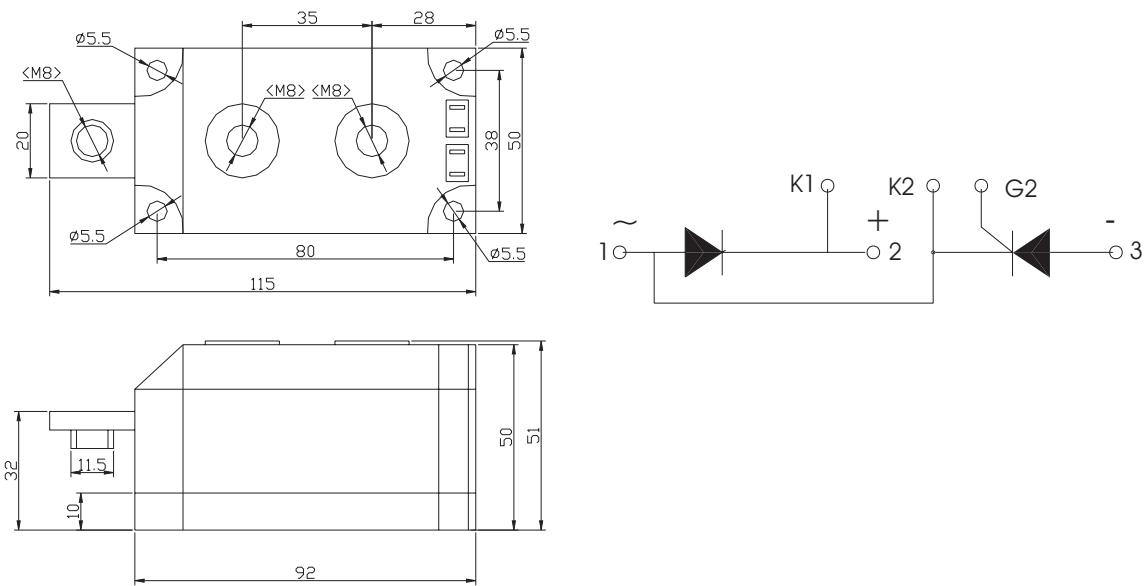


Fig. 8 - Outline Characteristics

Fig. 9 - Circuit Layout